

MT3238

N-Channel Power MOSFET

80V, 120A, 5.5mΩ



MT Semiconductor®

<http://www.mtsemi.com>

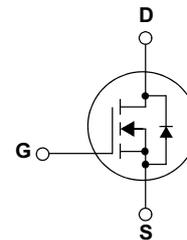
Features

- Max $R_{DS(on)} = 5.5m\Omega$ at $V_{GS} = 10V$, $I_D = 45A$
- Fast Switching Speed
- Low Gate Charge
- High Performance Trench Technology for Extr emely Low $R_{DS(on)}$
- High Power and Current Handling Capability
- RoHS Compliant

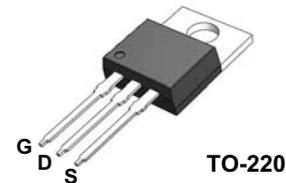
General Description

This N-Channel MOSFET is produced using MOS-TECH Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



Applications

- DC-DC primary bridge
- DC-DC Synchronous rectification
- Hot swap

MOSFET Maximum Ratings $T_C = 25^\circ C$ unless otherwise noted

| Symbol | Parameter | Rating | Unit |
|--|--|-----------------------------|--------------|
| Common Ratings ($T_C = 25^\circ C$ Unless Otherwise Noted) | | | |
| V_{DSS} | Drain-Source Voltage | 80 | V |
| V_{GSS} | Gate-Source Voltage | ± 25 | |
| T_J | Maximum Junction Temperature | 175 | $^\circ C$ |
| T_{STG} | Storage Temperature Range | 55 to 175 | $^\circ C$ |
| I_S | Diode Continuous Forward Current | $T_C = 25^\circ C$ 120 | A |
| Mounted on Large Heat Sink | | | |
| I_{DM} | | $T_C = 25^\circ C$ 480** | A |
| I_D | Continuous Drain Current | $T_C = 25^\circ C$ 120 | A |
| | | $T_C = 100^\circ C$ 85 | |
| P_D | Maximum Power Dissipation | $T_C = 25^\circ C$ 226 | W |
| | | $T_C = 100^\circ C$ 113 | |
| $R_{\theta JC}$ | Thermal Resistance-Junction to Case | 0.66 | $^\circ C/W$ |
| $R_{\theta JA}$ | Thermal Resistance-Junction to Ambient | 62.5 | |
| Avalanche Ratings | | | |
| E_{AS} | Avalanche Energy, Single Pulsed | $L = 0.5mH$ 630*** | mJ |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|--------|---------|-----------|------------|----------|
| MT3238 | MT3238 | TO-220 | - | - | 50 |

Electrical Characteristics ($T_c = 25^\circ\text{C}$ Unless Otherwise Noted)

| Symbol | Parameter | Test Conditions | | | | Unit |
|-------------------------------|----------------------------------|---|------|------|-----------|------------|
| | | | Min. | Typ. | Max. | |
| Static Characteristics | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $V_{GS}=0V, I_{DS}=250\mu A$ | 80 | | - | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=80V, V_{GS}=0V$ $T_J=85^\circ\text{C}$ | - | - | 1 | μA |
| | | | - | - | 10 | |
| $V_{GS(th)}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_{DS}=250\mu A$ | 2.0 | 3.0 | 4.0 | V |
| I_{GSS} | Gate Leakage Current | $V_{GS}=\pm 25V, V_{DS}=0V$ | - | - | ± 100 | nA |
| $R_{DS(ON)}$ | Drain-Source On-state Resistance | $V_{GS}=10V, I_{DS}=60A$ | - | 5.5 | 7.0 | m Ω |
| Diode Characteristics | | | | | | |
| V_{SD} | Diode Forward Voltage | $I_{SD}=60A, V_{GS}=0V$ | - | 0.8 | 1 | V |
| t_{rr} | Reverse Recovery Time | $I_{SD}=60A, dI_{SD}/dt=100A/\mu s$ | - | 46 | - | ns |
| Q_{rr} | Reverse Recovery Charge | | - | 98 | - | nC |

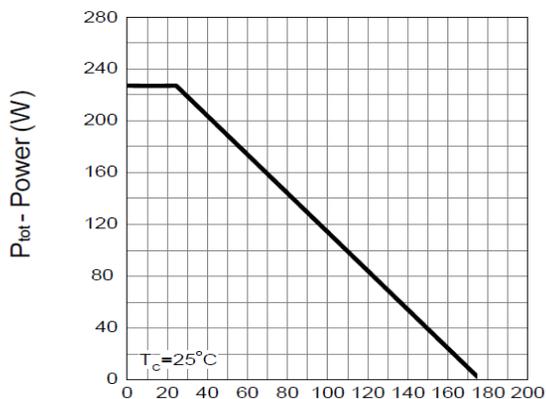
Electrical Characteristics (Cont.) ($T_c = 25^\circ\text{C}$ Unless Otherwise Noted)

| Symbol | Parameter | Test Conditions | | | | Unit |
|------------------------------------|------------------------------|---|------|------|------|----------|
| | | | Min. | Typ. | Max. | |
| Dynamic Characteristics | | | | | | |
| R_G | Gate Resistance | $V_{GS}=0V, V_{DS}=0V, F=1\text{MHz}$ | - | 0.6 | - | Ω |
| C_{iss} | Input Capacitance | $V_{GS}=0V,$ $V_{DS}=25V,$ Frequency=1.0MHz | - | 3680 | - | pF |
| C_{oss} | Output Capacitance | | - | 552 | - | |
| C_{rss} | Reverse Transfer Capacitance | | - | 192 | - | |
| $t_{d(ON)}$ | Turn-on Delay Time | $V_{DD}=40V, R_G=6\Omega,$ $I_{DS}=60A, V_{GS}=10V,$ | - | 23 | - | ns |
| T_r | Turn-on Rise Time | | - | 35 | - | |
| $t_{d(OFF)}$ | Turn-off Delay Time | | - | 77 | - | |
| T_f | Turn-off Fall Time | | - | 44 | - | |
| Gate Charge Characteristics | | | | | | |
| Q_g | Total Gate Charge | $V_{DS}=64V, V_{GS}=10V,$ $I_{DS}=60A$ | - | 87.9 | - | nC |
| Q_{gs} | Gate-Source Charge | | - | 15 | - | |
| Q_{gd} | Gate-Drain Charge | | - | 30 | - | |

Note * : Pulse test ; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

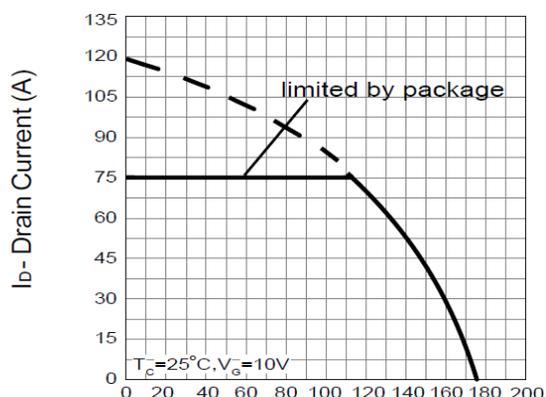
Typical Operating Characteristics

Power Dissipation



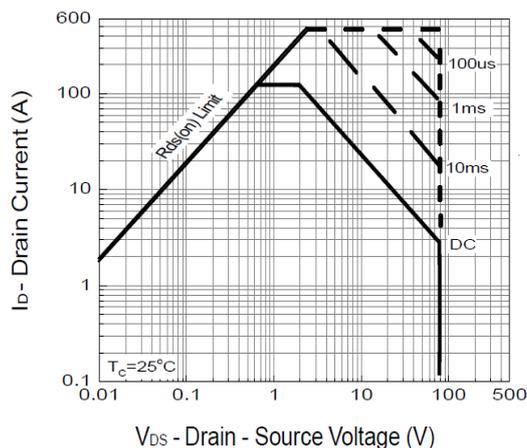
T_c - Case Temperature (°C)

Drain Current



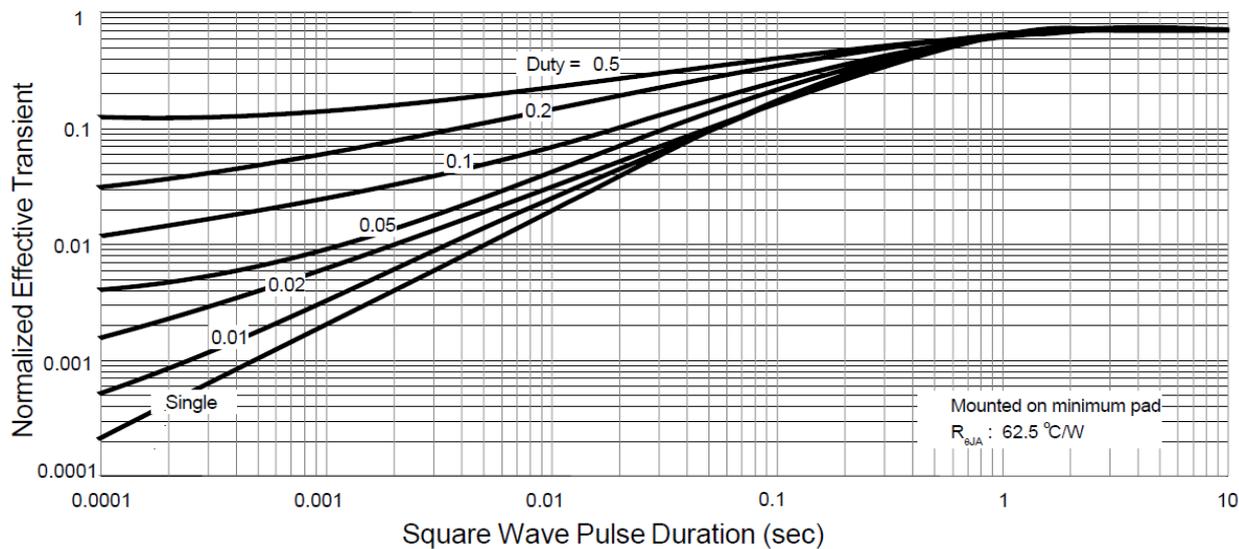
T_c -Case Temperature (°C)

Safe Operation Area



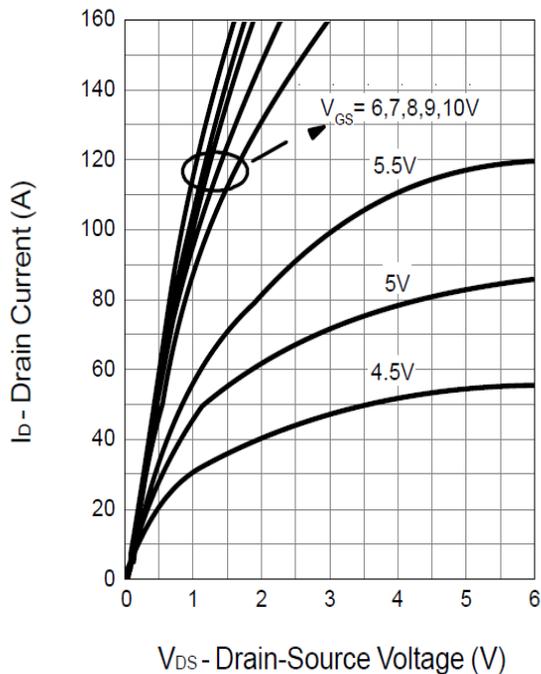
V_{DS} - Drain - Source Voltage (V)

Thermal Transient Impedance

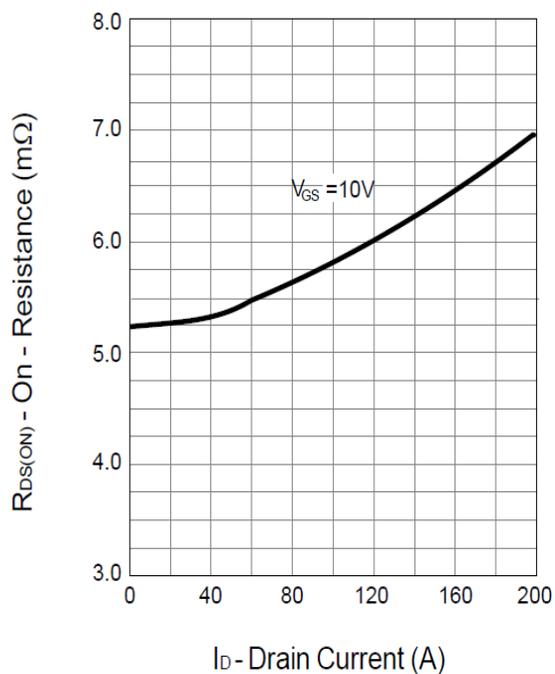


Typical Operating Characteristics (Cont.)

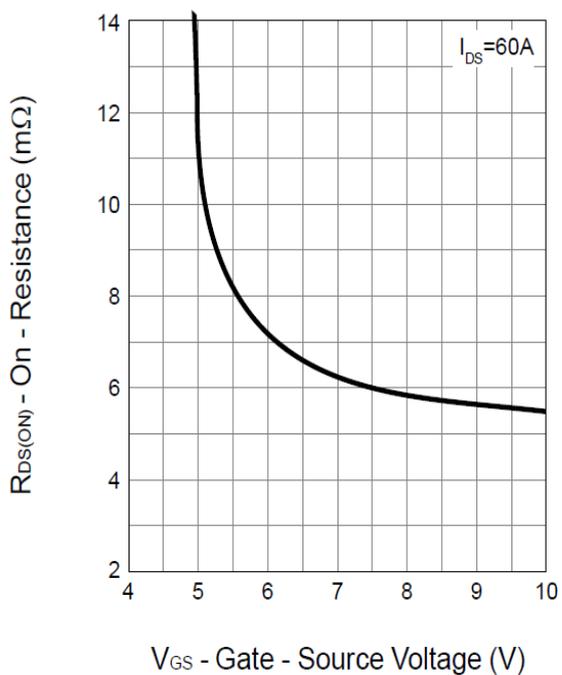
Output Characteristics



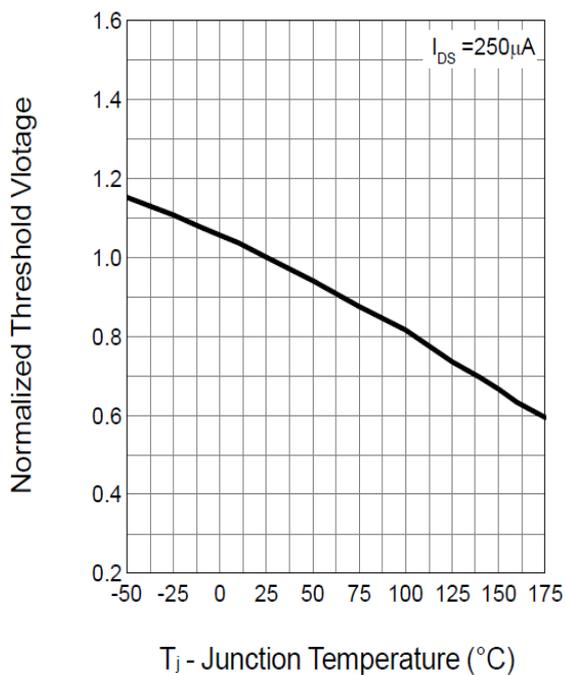
Drain-Source On Resistance



Drain-Source On Resistance

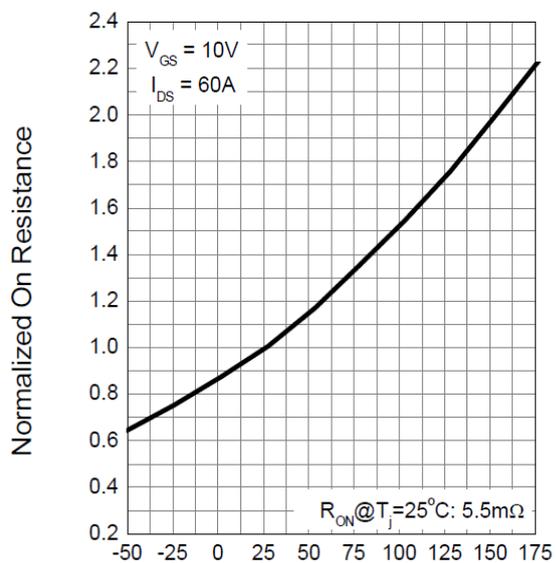


Gate Threshold Voltage



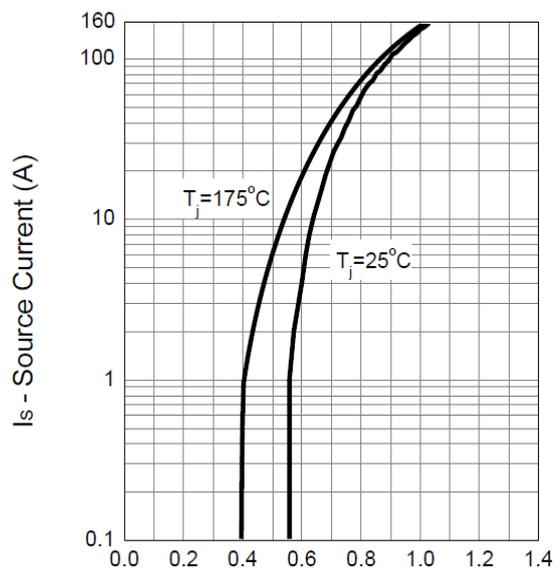
Typical Operating Characteristics (Cont.)

Drain-Source On Resistance



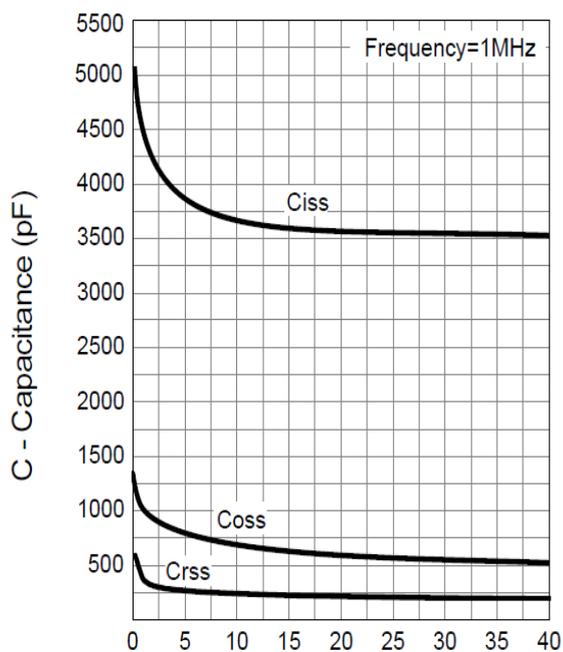
T_j - Junction Temperature (°C)

Source-Drain Diode Forward



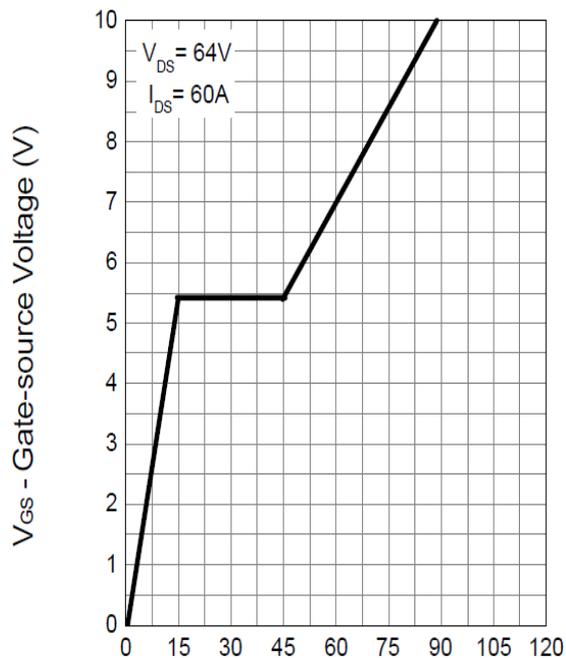
V_{SD} - Source-Drain Voltage (V)

Capacitance



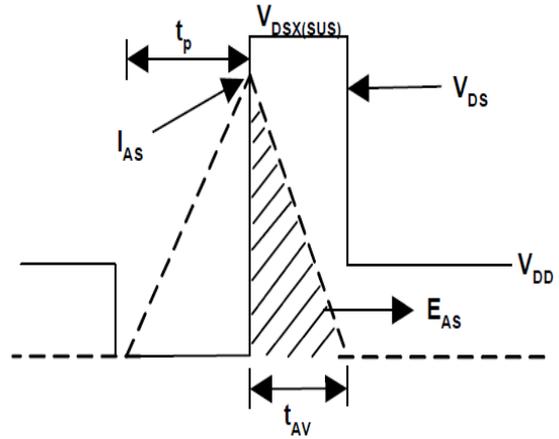
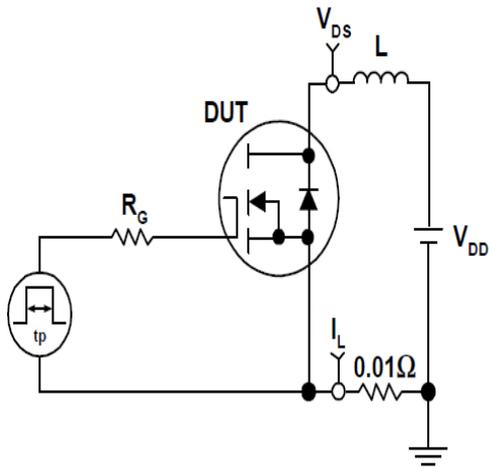
V_{DS} - Drain - Source Voltage (V)

Gate Charge

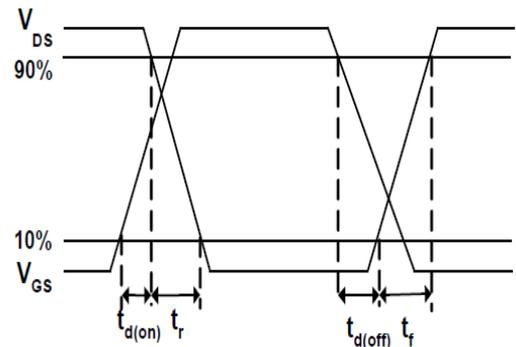
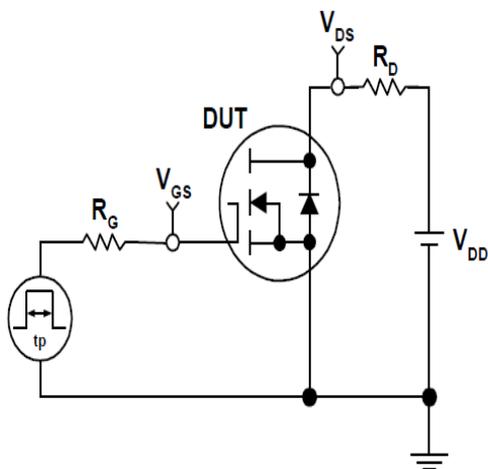


Q_G - Gate Charge (nC)

Avalanche Test Circuit and Waveforms



Avalanche Test Circuit and Waveforms



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